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With the principle of "Quality Parts, Customers Priority, Honest Operation, and Considerate Service", our business mainly focus on the distribution of electronic components. Line cards we deal with include Microchip, ALPS, ROHM, Xilinx, Pulse, ON, Everlight and Freescale. Main products comprise IC, Modules, Potentiometer, IC Socket, Relay, Connector. Our parts cover such applications as commercial, industrial, and automotives areas.

We are looking forward to setting up business relationship with you and hope to provide you with the best service and solution. Let us make a better world for our industry!



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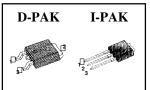
FEATURES

- ♦ Avalanche Rugged Technology
- ◆ Rugged Gate Oxide Technology
- ◆ Lower Input Capacitance
- ◆ Improved Gate Charge
- Extended Safe Operating Area
- Lower Leakage Current: 10μA (Max.) @ V_{DS} = 200V
- Lower $R_{DS(ON)}$: 0.335 Ω (Typ.)

00 V

 $R_{DS(on)} = \ 0.4\Omega$

 $I_D = 7.5 A$



1. Gate 2. Drain 3. Source

Absolute Maximum Ratings

Symbol	Characteristic	Value	Units	
V_{DSS}	Drain-to-Source Voltage	200	٧	
,	Continuous Drain Current (T _C =25°C)	7.5		
l _D	Continuous Drain Current (T _C =100°C)	4.7	Α	
I _{DM}	Drain Current-Pulsed (1)	26	Α	
V_{GS}	Gate-to-Source Voltage	±20	V	
E _{AS}	Single Pulsed Avalanche Energy (2)	37	mJ	
I _{AR}	Avalanche Current (1)	7.5	Α	
E _{AR}	Repetitive Avalanche Energy (1)	4.8	mJ	
dv/dt	Peak Diode Recovery dv/dt (3)	5	V/ns	
	Total Power Dissipation (T _A =25°C) *	2.5	W	
P_{D}	Total Power Dissipation (T _C =25°C)	48	W	
	Linear Derating Factor	0.38	W/°C	
т т	Operating Junction and	55 to .450		
T_J , T_STG	Storage Temperature Range	- 55 to +150	_	
	Maximum Lead Temp. for Soldering	000	°C	
T _L	Purposes, 1/8. from case for 5-seconds	300		

Thermal Resistance

Symbol	Characteristic	Тур.	Max.	Units
$R_{ heta JC}$	Junction-to-Case	-	2.6	
$R_{ heta JA}$	Junction-to-Ambient *		50	°C/W
$R_{ heta JA}$	Junction-to-Ambient		110	

^{*} When mounted on the minimum pad size recommended (PCB Mount).



Electrical Characteristics (T_C=25°C unless otherwise specified)

Symbol	Characteristic	Min.	Тур.	Max.	Units	Test Condition
BV _{DSS}	Drain-Source Breakdown Voltage	200	1		٧	$V_{GS} = 0V, I_D = 250 \mu A$
$\Delta BV/\Delta T_J$	Breakdown Voltage Temp. Coeff.		0.25		V/°C	I _D =250μA
$V_{GS(th)}$	Gate Threshold Voltage	1.0	1	2.0	٧	$V_{DS} = 5V, I_{D} = 250 \mu A$
	Gate-Source Leakage, Forward			100	nA	V _{GS} =20V
I _{GSS}	Gate-Source Leakage, Reverse			-100	ш	V _{GS} =-20V
	Drain to Course Leekens Current			10		V _{DS} =200V
I _{DSS}	Drain-to-Source Leakage Current			100	μΑ	$V_{DS} = 160V, T_{C} = 125^{\circ}C$
Ь	Static Drain-Source					V 5VI 0.75A (4)
R _{DS(on)}	On-State Resistance			0.4	Ω	$V_{GS} = 5V, I_D = 3.75A$ (4)
g_{fs}	Forward Transconductance		4.2		Ω	$V_{DS} = 40V, I_D = 4.5A$ (4)
C _{iss}	Input Capacitance		580	755		\/ 0\/\/ 25\/f 1MU>
C _{oss}	Output Capacitance		90	115	pF	V_{GS} =0V, V_{DS} =25V,f =1MHz See Fig 5
C_{rss}	Reverse Transfer Capacitance		44	55		See Fig 5
t _{d(on)}	Turn-On Delay Time		8	25		$V_{DD} = 100V, I_{D} = 9A,$
t _r	Rise Time		6	20	20	
$t_{d(off)}$	Turn-Off Delay Time		30	70	ns	$R_{G}=6\Omega$
t _f	Fall Time		9	30		See Fig 13 (4) (5)
Q_g	Total Gate Charge		18.6	27		V_{DS} =160 V , V_{GS} =5 V ,
Q_{gs}	Gate-Source Charge		3.5		nC	I _D =9A
Q_{gd}	Gate-Drain (. Miller.) Charge		8.3			See Fig 6 & Fig 12 (4) (5)

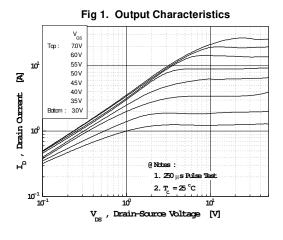
Source-Drain Diode Ratings and Characteristics

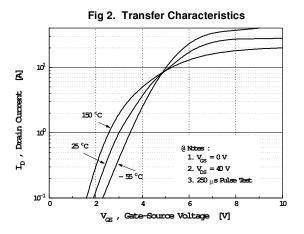
	Symbol	Characteristic	Min.	Тур.	Max.	Units	Test Condition
	I _S	Continuous Source Current			7.5	^	Integral reverse pn-diode
	I _{SM}	Pulsed-Source Current (1)		-	26	Α	in the MOSFET
	V_{SD}	Diode Forward Voltage (4)		-	1.5	V	T _J =25°C,I _S =7.5A,V _{GS} =0V
	t _{rr}	Reverse Recovery Time		158		ns	$T_J=25$ °C, $I_F=9A$
Ĺ	Q_{rr}	Reverse Recovery Charge		0.78		μС	$di_F/dt=100A/\mu s$ (4)

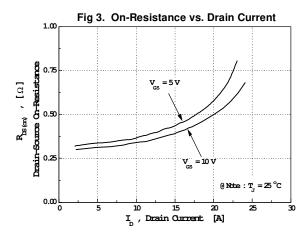
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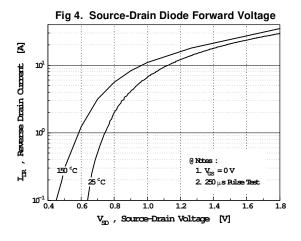
- . Repetitive Rating: Pulse Width Limited by Maximum Junction Temperature
- . L=1mH, I $_{\rm AS}$ =7.5A, V $_{\rm DD}$ =50V, R $_{\rm G}$ =27 Ω , Starting T $_{\rm J}$ =25°C
- . $I_{SD} \le 9A$, $di/dt \le 220A/\mu s$, $V_{DD} \le BV_{DSS}$, Starting $T_J = 25^{\circ}C$
- . Pulse Test: Pulse Width = $250\mu s$, Duty Cycle $\leq 2\%$
- Essentially Independent of Operating Temperature

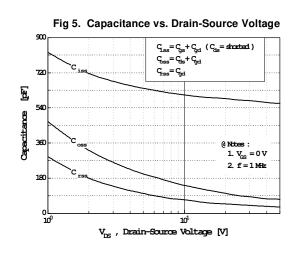


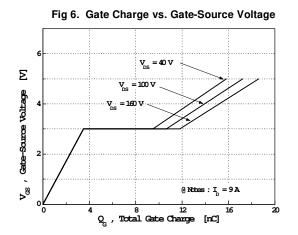




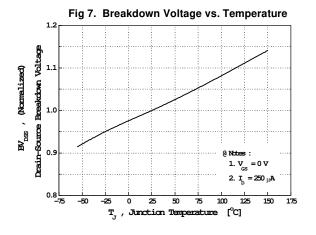


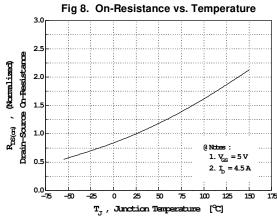


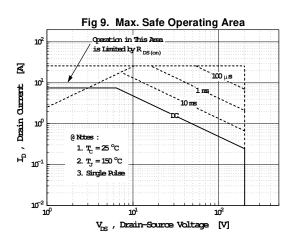


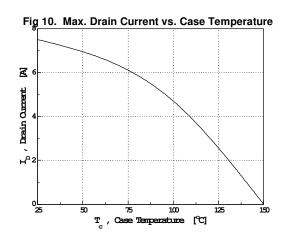












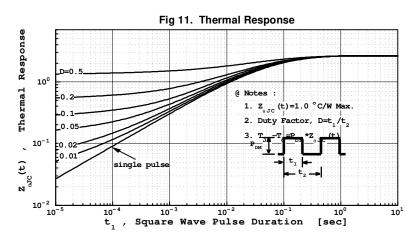




Fig 12. Gate Charge Test Circuit & Waveform

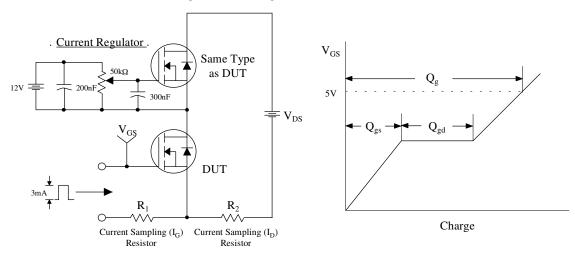


Fig 13. Resistive Switching Test Circuit & Waveforms

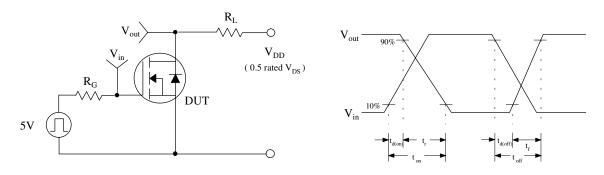


Fig 14. Unclamped Inductive Switching Test Circuit & Waveforms

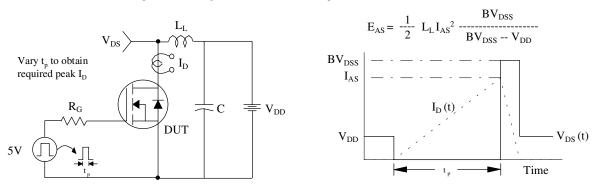
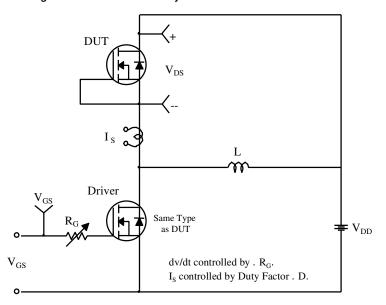
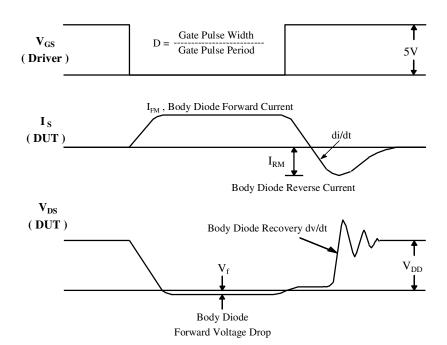




Fig 15. Peak Diode Recovery dv/dt Test Circuit & Waveforms







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